## Notice of References Cited Application/Control No. 10/822,167 Examiner Eric Wendler Applicant(s)/Patent Under Reexamination CHAE ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,910,917	06-1999	Fukuzumi, Tomoya	365/185.33
*	В	US-6,097,666	08-2000	Sakui et al.	365/230.06
*	С	US-5,625,590	04-1997	Choi et al.	365/185.17
*	D	US-5,332,922	07-1994	Oguchi et al.	257/723
*	Е	US-6,278,654	08-2001	Roohparvar, Frankie F.	365/238.5
*	F	US-2003/0117886	06-2003	Shiga et al.	365/233
*	G	US-2006/0077721	04-2006	Sugio, Kenichiro	365/185.33
	I	US-			
	_	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q				(1)	
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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